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Notice of References Cited		Application/Control No. 09/626,181 60/828562	Applicant(s)/Patent Under Reexamination NAKATA ET AL.	
		Examiner Eugene Lee	Art Unit 2815 2812	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
✓	A	US-6,138,481 A	10-2000	Aoki, Tetsuro	430/7
✓	B	US-5,053,765	10-1991	Sonehara et al.	340/815.43
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
✓	N	JP 09096712 A	04-1997	Japan	MARUMICHI, HIROTAKE	G02B 05/20
✓	O	JP 08297206 A	11-1996	Japan	SEGAWA, YUJI	G02B 05/20
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Considered all of the above J. Kennedy 9/28/05

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Notice of References Cited		Application/Control No. 09/626,181 10/828562	Applicant(s)/Patent Under Reexamination NAKATA ET AL.	
		Examiner J. Kennedy Eugene Lee	Art Unit 2015 2812	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
✓	A	US-6,340,547	01-2002	Chen et al.	430/22
✓	B	US-6,143,450	11-2000	Sobue et al.	347/106
✓	C	US-6136481	10-2000	Aoki	430/7
✓	D	US-5935741	08-1999	Kim et al.	430/7
✓	E	US-5850276	12-1998	Ochi et al.	399/158
✓	F	US-5320920	06-1994	Isoda et al.	430/7
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
✓	N	09043416	02-1997	JPO	Yamaguchi et al.	
✓	O	08146371	06-1996	JPO	Taniguchi	
✓	P	02158120	06-1990	JPO	Maeda	438/975
✓	Q	01137238	05-1989	JPO	Takahara	257/797
✓	R	07072473	03-1995	JPO	Inoue	
	S					
	T					

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INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

Deckel Number (Optional) NEC 00FN041	Application Number 1D/828562 -09/626,181
Applicant(s) NAKATA et al.	
Filing Date July 27, 2000	Group Art Unit -2815- 2812

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
62	08-029614	02.02.1996	JAPAN (abstracts only)	G02B	5/20		
62	63-026634	04.02.1998	JAPAN (abstracts only)	G02F	1/135		
62	10-209202	07.08.1998	JAPAN (abstracts only)	H 01L	21/60		
62	63-243915	11.10.1988	JAPAN (abstracts only)	G02F	1/13		

OTHER DOCUMENTS (*Including Author, Title, Date, Pertinent Pages, Etc.*)

EXAMINER	<i>G. D. A.</i>	DATE CONSIDERED <u>9/20/03</u>

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FORMATION DISCLOSURE STATEMENT
(Use several sheets if necessary)

Docket Number (Optional) NEC 00FN041	Application Number 10/828562 09/626,181
Applicant(s) NAKATA et al.	
Filing Date July 27, 2000	Group Art Unit 2815 2812

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
EL	09-096712	08.04.1997	JAPAN	G02B	S/20		✓

OTHER DOCUMENTS (*Including Author, Title, Date, Pertinent Pages, Etc.*)

A graph showing two curves on a grid. The x-axis is labeled 'X' and the y-axis is labeled 'Y'. One curve starts at approximately (0, 0.1) and increases steadily to about (10, 1.0). The other curve starts at approximately (0, 0.3) and increases more steeply, reaching about (10, 1.0) at the same point as the first curve.

EXAMINER

DATE CONSIDERED

11/10/02

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